

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/655,899	YANG ET AL.
	Examiner	Art Unit
	Y. J. Han	2838

SEARCHED			
Class	Subclass	Date	Examiner
363	21.1		
	21.18		
	41		
	56.01		
	97		
	49		
323	299		
	315		
	901	2/05	JP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
363	49		
	56.01		
	21.1		
323	299		
	901	2/05	AS